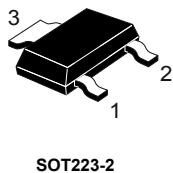


## N-channel 600 V, 1.00 $\Omega$ typ., 5.5 A MDmesh M2 Power MOSFET in an SOT223-2 package

### Features



Order code	V <sub>DS</sub>	R <sub>DS(on)</sub> max.	I <sub>D</sub>
STN6N60M2	600 V	1.25 $\Omega$	5.5 A

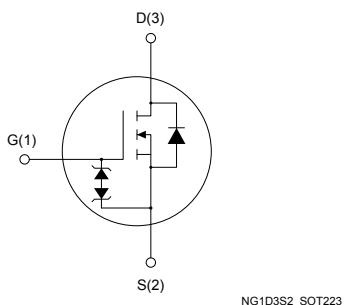
- Extremely low gate charge
- Excellent output capacitance (C<sub>oss</sub>) profile
- 100% avalanche tested
- Zener-protected

### Applications

- Switching applications

### Description

This device is an N-channel Power MOSFET developed using MDmesh M2 technology. Thanks to its strip layout and an improved vertical structure, the device exhibits low on-resistance and optimized switching characteristics, rendering it suitable for the most demanding high efficiency converters.



#### Product status link

[STN6N60M2](#)

#### Product summary

Order code	STN6N60M2
Marking	6N60M2
Package	SOT223-2
Packing	Tape and reel

## 1 Electrical ratings

**Table 1. Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{GS}$	Gate-source voltage	$\pm 25$	V
$I_D$ <sup>(1)</sup>	Drain current (continuous) at $T_C = 25^\circ\text{C}$	5.5	A
$I_D$ <sup>(1)</sup>	Drain current (continuous) at $T_C = 100^\circ\text{C}$	3.5	A
$I_{DM}$ <sup>(2)</sup>	Drain current (pulsed)	8	A
$P_{TOT}$	Total power dissipation at $T_S = 25^\circ\text{C}$	6	W
$dv/dt^{(3)}$	Peak diode recovery voltage slope	15	V/ns
$dv/dt^{(4)}$	MOSFET dv/dt ruggedness	50	
$T_J$	Operating junction temperature range	-55 to 150	$^\circ\text{C}$
$T_{stg}$	Storage temperature range		

1. Limited by maximum junction temperature.
2. Pulse width limited by safe operating area.
3.  $I_{SD} \leq 5.5 \text{ A}$ ,  $di/dt = 400 \text{ A}/\mu\text{s}$ ;  $V_{DS(\text{peak})} < V_{(BR)DSS}$ ;  $V_{DD} = 400 \text{ V}$
4.  $V_{DS} \leq 480 \text{ V}$

**Table 2. Thermal data**

Symbol	Parameter	Value	Unit
$R_{thj-S}$	Thermal resistance junction-solder point	20	$^\circ\text{C}/\text{W}$
$R_{thj-pcb}$ <sup>(1)</sup>	Thermal resistance junction-pcb	38	$^\circ\text{C}/\text{W}$

1. When mounted on 1 inch<sup>2</sup> FR-4, 2 Oz copper board.

**Table 3. Avalanche characteristics**

Symbol	Parameter	Value	Unit
$I_{AR}$	Avalanche current, repetitive or not repetitive (pulse width limited by $T_{jmax.}$ )	0.8	A
$E_{AS}$	Single pulse avalanche energy (starting $T_j = 25^\circ\text{C}$ , $I_D = I_{AR}$ , $V_{DD} = 50 \text{ V}$ )	83	mJ

## 2 Electrical characteristics

$T_C = 25^\circ\text{C}$  unless otherwise specified

Table 4. On/off-state

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(\text{BR})\text{DSS}}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	600			V
$I_{\text{DS}}^{\text{SS}}$	Zero gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V}$			1	$\mu\text{A}$
		$V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V}; T_C = 125^\circ\text{C}$ (1)			100	$\mu\text{A}$
$I_{GSS}$	Gate body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			$\pm 10$	$\mu\text{A}$
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	2	3	4	V
$R_{DS(\text{on})}$	Static drain-source on-resistance	$V_{GS} = 10 \text{ V}, I_D = 2 \text{ A}$		1.00	1.25	$\Omega$

1. Defined by design, not subject to production test.

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input capacitance	$V_{DS} = 100 \text{ V}, f = 1 \text{ MHz}, V_{GS} = 0 \text{ V}$	-	220	-	pF
$C_{oss}$	Output capacitance		-	12.5	-	pF
$C_{rss}$	Reverse transfer capacitance		-	3.3	-	pF
$C_{oss \text{ eq.}}$ (1)	Equivalent output capacitance	$V_{DS} = 0 \text{ to } 480 \text{ V}, V_{GS} = 0 \text{ V}$	-	23	-	pF
$R_G$	Intrinsic gate resistance	$f = 1 \text{ MHz}, I_D = 0 \text{ A}$	-	9	-	$\Omega$
$Q_g$	Total gate charge	$V_{DD} = 480 \text{ V}, I_D = 4 \text{ A}, V_{GS} = 0 \text{ to } 10 \text{ V}$ (see Figure 15. Test circuit for gate charge behavior)	-	6.2	-	nC
$Q_{gs}$	Gate-source charge		-	1.3	-	nC
$Q_{gd}$	Gate-drain charge		-	2.7	-	nC

1.  $C_{oss \text{ eq.}}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$ .

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 300 \text{ V}, I_D = 2 \text{ A}, R_G = 4.7 \Omega,$	-	6.4	-	ns
$t_r$	Rise time	$V_{GS} = 10 \text{ V}$ (see Figure 14. Test circuit for resistive load switching times and Figure 19. Switching time waveform)	-	6.2	-	ns
$t_{d(off)}$	Turn-off delay time		-	18	-	ns
$t_f$	Fall time		-	15.8	-	ns

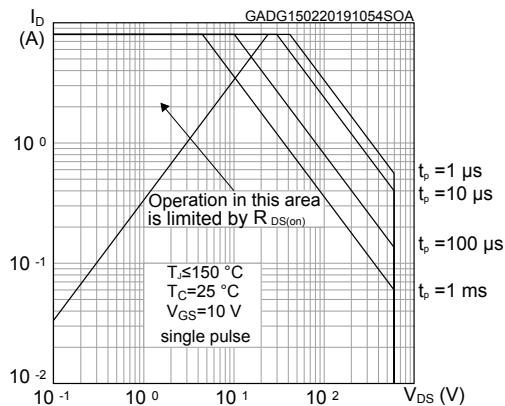
**Table 7. Source-drain diode**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}$ <sup>(1)</sup>	Source-drain current		-		5.5	A
$I_{SDM}$ <sup>(2)</sup>	Source-drain current (pulsed)		-		8	A
$V_{SD}$ <sup>(3)</sup>	Forward on voltage	$I_{SD} = 4 \text{ A}, V_{GS} = 0 \text{ V}$	-		1.6	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 4 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}, V_{DD} = 60 \text{ V},$ (see Figure 16. Test circuit for inductive load switching and diode recovery times)	-	229		ns
$Q_{rr}$	Reverse recovery charge		-	721		nC
$I_{RRM}$	Reverse recovery current		-	6.3		A
$t_{rr}$	Reverse recovery time	$I_{SD} = 4 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}, V_{DD} = 60 \text{ V},$ $T_j = 150^\circ\text{C}$ (see Figure 16. Test circuit for inductive load switching and diode recovery times)	-	288		ns
$Q_{rr}$	Reverse recovery charge		-	936		nC
$I_{RRM}$	Reverse recovery current		-	6.5		A

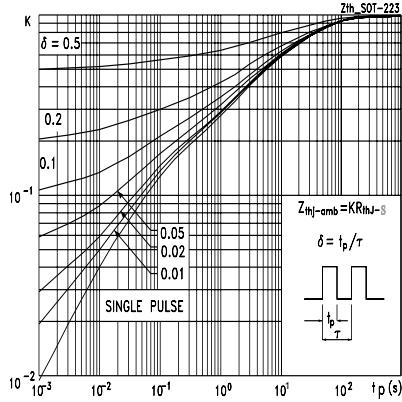
1. Limited by maximum junction temperature.
2. Pulse width limited by safe operating area.
3. Pulsed: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%.

## 2.1 Electrical characteristics (curves)

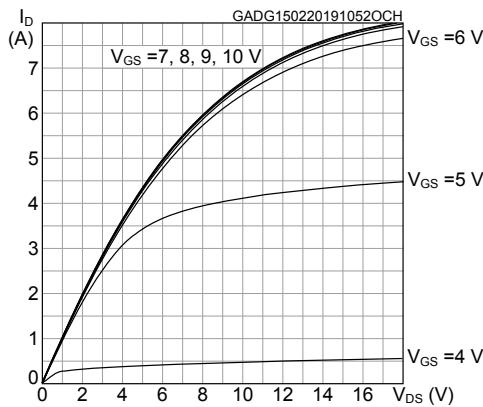
**Figure 1. Safe operating area**



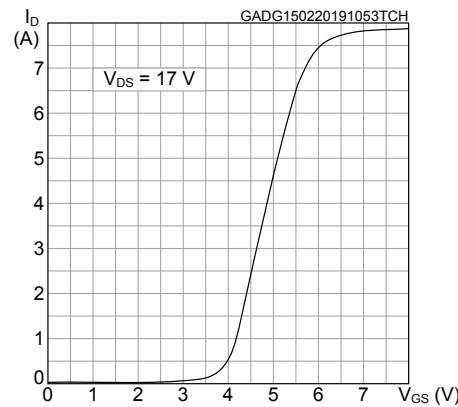
**Figure 2. Thermal impedance**



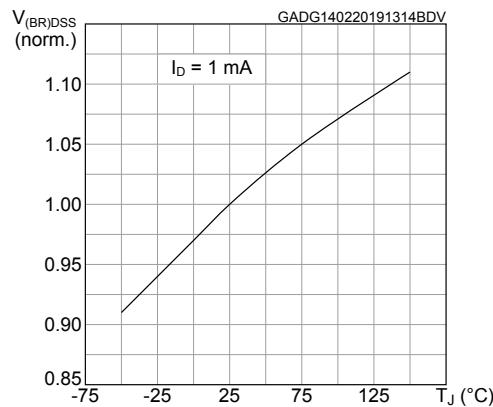
**Figure 3. Output characteristics**



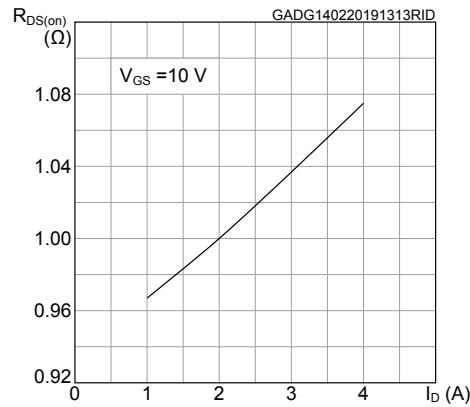
**Figure 4. Transfer characteristics**



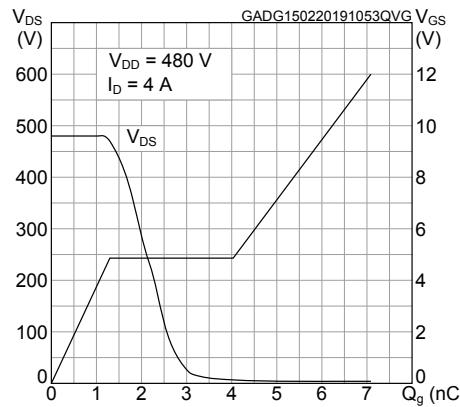
**Figure 5. Normalized  $V_{BR(DSS)}$  vs temperature**



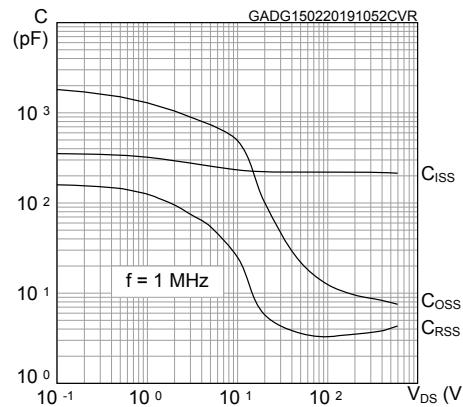
**Figure 6. Static drain-source on-resistance**



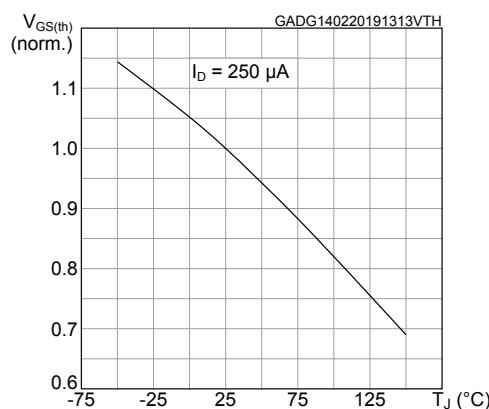
**Figure 7. Gate charge vs gate-source voltage**



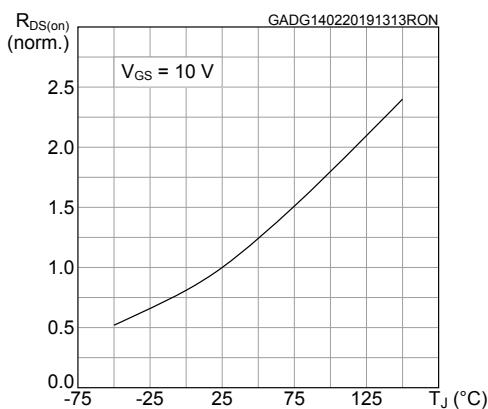
**Figure 8. Capacitance variations**



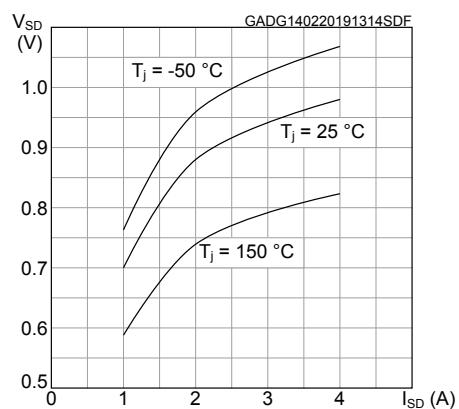
**Figure 9. Normalized gate threshold voltage vs temperature**



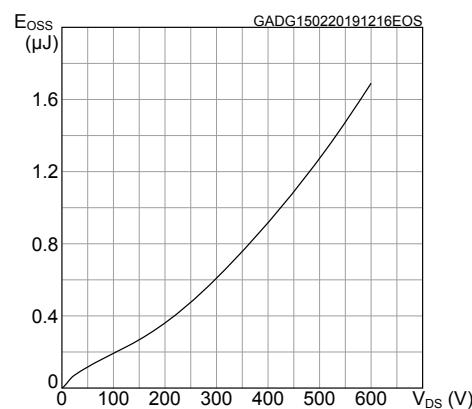
**Figure 10. Normalized on-resistance vs temperature**



**Figure 11. Source-drain diode forward characteristics**

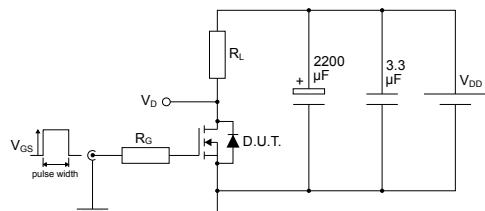


**Figure 12. Output capacitance stored energy**



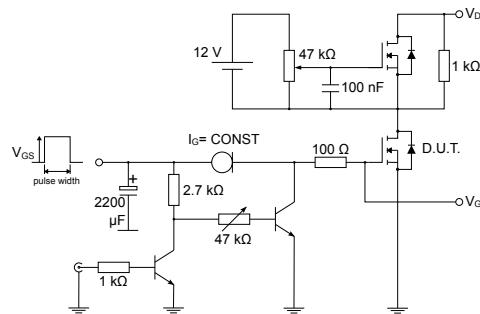
### 3 Test circuits

**Figure 13.** Test circuit for resistive load switching times



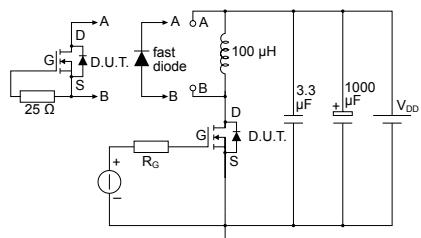
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**Figure 14.** Test circuit for gate charge behavior



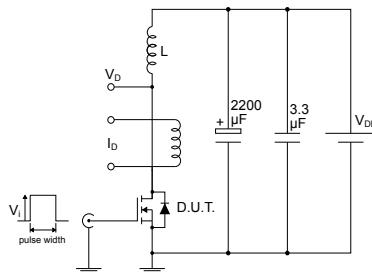
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**Figure 15.** Test circuit for inductive load switching and diode recovery times



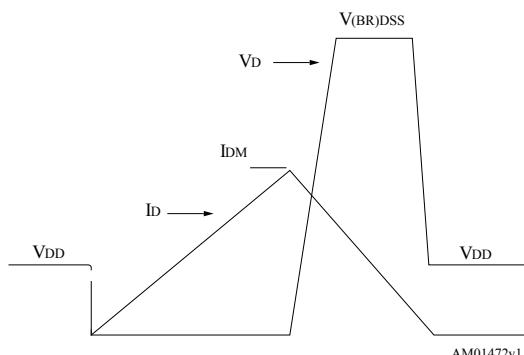
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**Figure 16.** Unclamped inductive load test circuit



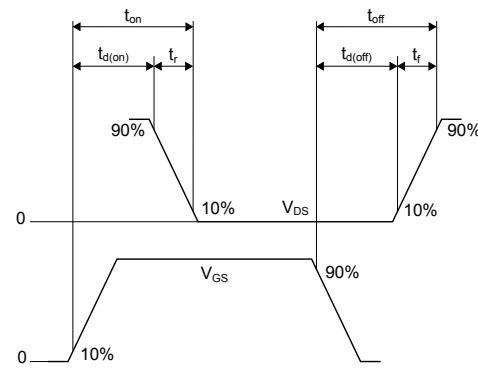
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**Figure 17.** Unclamped inductive waveform



AM01472v1

**Figure 18.** Switching time waveform



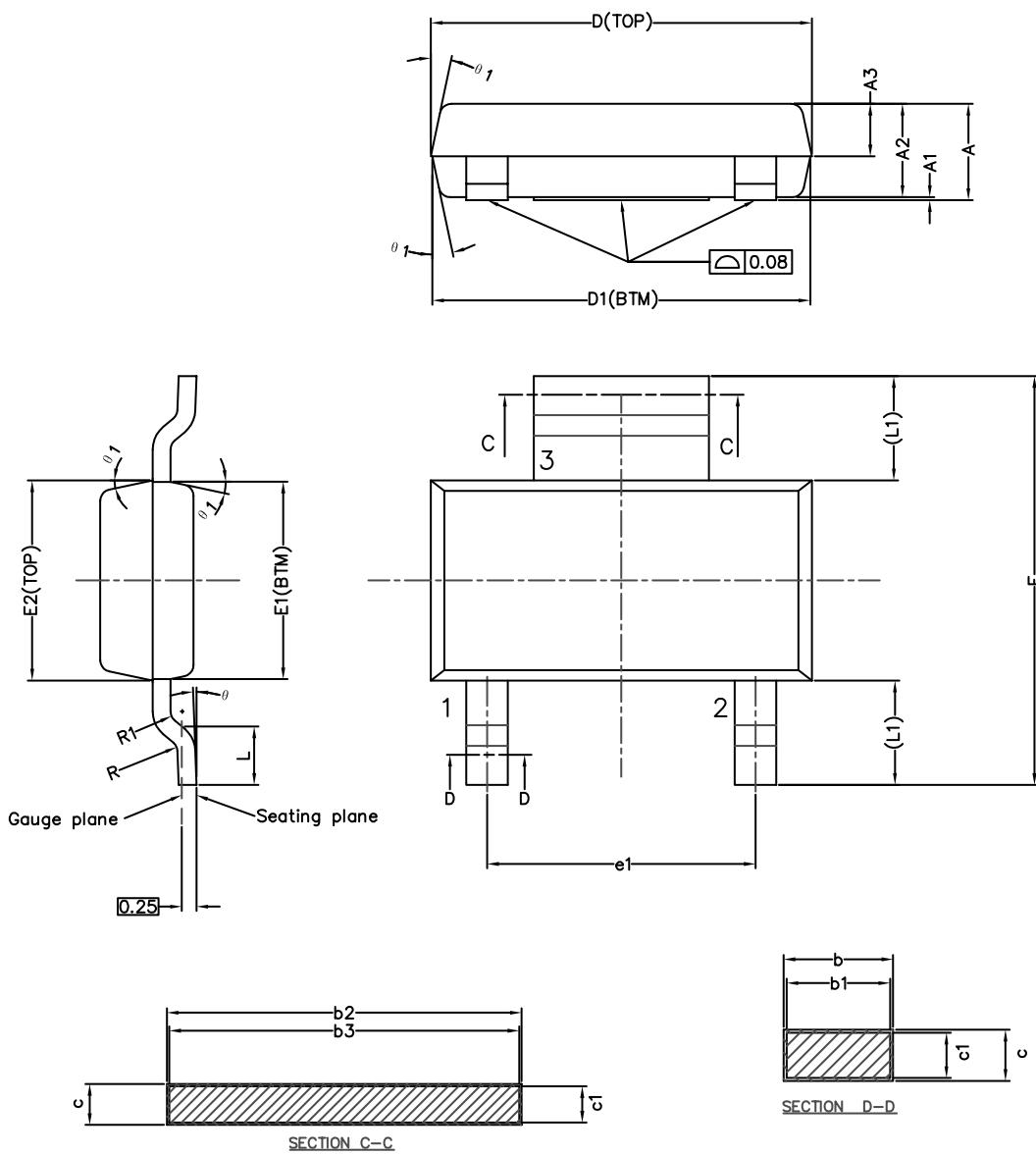
AM01473v1

## 4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK packages, depending on their level of environmental compliance. ECOPACK specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com). ECOPACK is an ST trademark.

### 4.1 SOT223-2 package information

Figure 19. SOT223-2 package outline

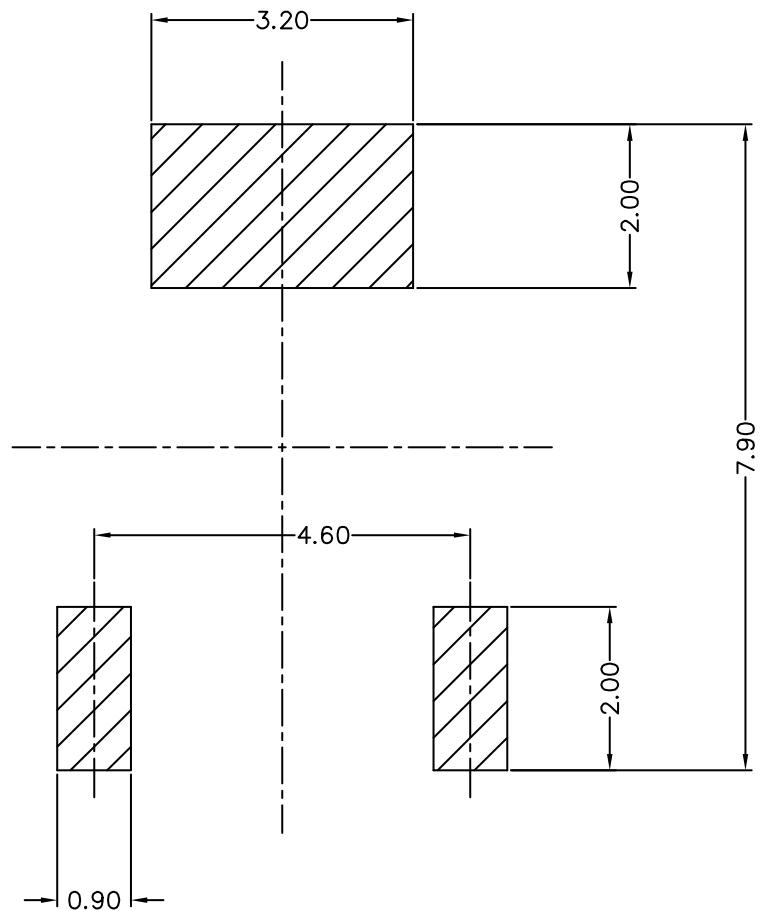


DM00320690\_2

**Table 8.** SOT223-2 package mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A			1.80
A1	0.02		0.10
A2	1.50	1.60	1.70
A3	0.80	0.90	1.00
b	0.67		0.80
b1	0.66	0.71	0.76
b2	2.96		3.09
b3	2.95	3.00	3.05
c	0.30		0.35
c1	0.29	0.30	0.31
D	6.48	6.53	6.58
D1	6.43	6.48	6.53
E	6.80		7.20
E1	3.30	3.38	3.48
E2	3.33	3.43	3.53
e1	4.50	4.60	4.70
L	0.80	1.00	1.20
L1	1.78 REF		
R	0.10		
R1	0.10		
θ	0°		8°
θ1	10°	12°	14°

**Figure 20.** SOT223-2 recommended footprint (dimensions are in mm)



DM00320690\_FP

## Revision history

**Table 9. Document revision history**

Date	Revision	Changes
18-Feb-2019	1	First release.
21-May-2020	2	Updated <a href="#">Table 1. Absolute maximum ratings</a> and <a href="#">Table 7. Source-drain diode</a> .

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